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**Statistical methods in process  
management — Capability and  
performance —**

**Part 3:  
Machine performance studies for  
measured data on discrete parts**

*Méthodes statistiques dans la gestion de processus — Aptitude et  
performance —*

*Partie 3: Études de performance de machines pour des données  
mesurées sur des parties discrètes*



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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see [www.iso.org/iso/foreword.html](http://www.iso.org/iso/foreword.html).

This document was prepared by Technical Committee ISO/TC 69, *Applications of statistical methods*, Subcommittee SC 4, *Applications of statistical methods in product and process management*.

This second edition cancels and replaces the first edition (ISO 22514-3:2008), which has been technically revised.

The main changes compared to the previous edition are as follows:

- updated and improved figures and computer outputs.

A list of all parts in the ISO 22514 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

## Introduction

This document has been prepared to provide guidance in circumstances where a study is necessary to determine if the output from a machine, for example, is acceptable according to some criteria. Such circumstances are common in engineering when the purpose for the study is part of an acceptance trial. These studies can also be used when diagnosis is required concerning a machine's current level of performance or as part of a problem-solving effort. The method is very versatile and has been applied to many situations.

Machine performance studies of this type provide information about the behaviour of a machine under very restricted conditions such as limiting, as far as possible, external sources of variation that are commonplace within a process, e.g. multi-factor and multi-level situations. The data gathered in a study might come from items made consecutively, although this may be altered according to the study requirements. The data are assumed to have been, generally, gathered manually.

The study procedure and reporting are of interest to engineers, supervisors and management wishing to establish whether a machine should be purchased or put in for maintenance, to assist in problem-solving or to understand the level of variation due to the machine itself.



# Statistical methods in process management — Capability and performance —

## Part 3: Machine performance studies for measured data on discrete parts

### 1 Scope

This document describes the steps for conducting short-term performance studies that are typically performed on machines (including devices, appliances, apparatuses) where parts produced consecutively under repeatability conditions are considered. The number of observations to be analysed vary according to the patterns the data produce, or if the runs (the rate at which items are produced) on the machine are low in quantity. The methods are not considered suitable where the sample size produced is less than 30 observations. Methods for handling the data and carrying out the calculations are described. In addition, machine performance indices and the actions required at the conclusion of a machine performance study are described.

This document is not applicable when tool wear patterns are expected to be present during the duration of the study, nor if autocorrelation between observations is present. The situation where a machine has captured the data, sometimes thousands of data points collected in a minute, is not considered suitable for the application of this document.

### 2 Normative references

There are no normative references in this document.

### 3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

### 4 Symbols

$P$	probability
$P_m$	machine performance index
$P_{mk_L}$	lower machine performance index
$P_{mk_U}$	upper machine performance index
$P_{mk}$	minimum machine performance index
$f$	absolute frequency